JSCJ

# ESD Report

Report NO.: MOS-E260427

## 1. Product Information

**Supplier :** JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO.,LTD.

| | |
|---|---|
| **Part Number:** | CJWQ014CP120M2H |
| **Package Type:** | TO-247-4L |
| **Report Date:** | August-2026 |

## 2. Reference Standard

| Item | Standards |
|---|---|
| 1.Human-Body Model(HBM) | JESD22-A114 |
| 2.Machine Model(MM) | JESD22-A115 |

## 3. Classification Criteria

| HBM Classification level | |
|---|---|
| Level | Test Voltage |
| CLASS 0 | ≤ 250V |
| CLASS 1A | > 250V to ≤ 500V |
| CLASS 1B | > 500V to ≤ 1000V |
| CLASS 1C | > 1000V to ≤ 2000V |
| CLASS 2 | > 2000V to ≤ 4000V |
| CLASS 3A | > 4000V to ≤ 8000V |
| CLASS 3B | > 8000V |

| MM Classification level | |
|---|---|
| Level | Test Voltage |
| CLASS A | < 200V |
| CLASS B | ≧ 200V to < 400V |
| CLASS C | ≧ 400V |

## 4. Test Result

| Test Item | Test Condition | Samples | Class Level |
|---|---|---|---|
| HBM | Interval:1s 3Times /200V~8000V step:200V(±) | 5PCS | CLASS 3A |
| MM | Interval:1s 3Times /200V~800V step:200V(±) | 5PCS | CLASS C |

## Notes:

The failure criterion for the ESD test is based on whether the Device Under Test (DUT) meets its product specification (datasheet). Specifically, after being subjected to the specified ESD pulse stress, the device must undergo electrical parameter testing and functional checks. The device shall be considered failed if any of the following conditions occur:

1) Electrical parameters deviate from the limits specified in the datasheet;
2) Logic functions or preset functions cannot be realized.

Remark: JSCJ Laboratory reserves the right of final interpretation of this report